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N-Channel PowerTrench[®] MOSFET 30 V, 12 A, 11.5 m Ω

Features

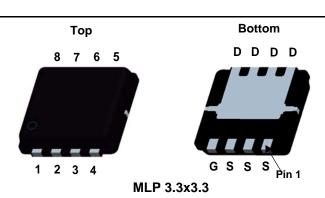
- Max $r_{DS(on)}$ = 11.5 m Ω at V_{GS} = 10 V, I_D = 12 A
- Max $r_{DS(on)}$ = 14.5 m Ω at V_{GS} = 4.5 V, I_D = 10 A
- High performance technology for extremely low r_{DS(on)}
- Termination is Lead-free and RoHS Compliant

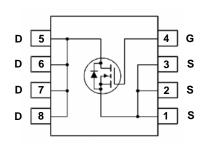
General Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced Power Trench[®] process that has been especially tailored to minimize the on-state resistance. This device is well suited for Power Management and load switching applications common in Notebook Computers and Portable Battery Packs.

Applications

- DC/DC Buck Converters
- Notebook battery power management
- Load Switch in Notebook





MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Parameter			Ratings	Units
V _{DS}	Drain to Source Voltage		30	V	
V _{DSt}	Drain to Source Transient Voltage (tTransient	< 100 ns)		33	V
V _{GS}	Gate to Source Voltage		(Note 4)	±20	V
	Drain Current -Continuous (Package limited)	T _C = 25°C		20	
I _D	-Continuous (Silicon limited)	$T_{C} = 25^{\circ}C$		38	•
	-Continuous	$T_A = 25^{\circ}C$	(Note 1a)	12	— A
	-Pulsed			50	
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	21	mJ
P _D	Power Dissipation	T _C = 25°C		25	14/
	Power Dissipation T _A = 25		(Note 1a)	2.4	W
T _J , T _{STG}	Operating and Storage Junction Temperature Range			-55 to +150	°C

Thermal Characteristics

$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case		5.0	°C/W	
$R_{ extsf{ heta}JA}$	Thermal Resistance, Junction to Ambient (Not	te 1a)	53	C/VV	

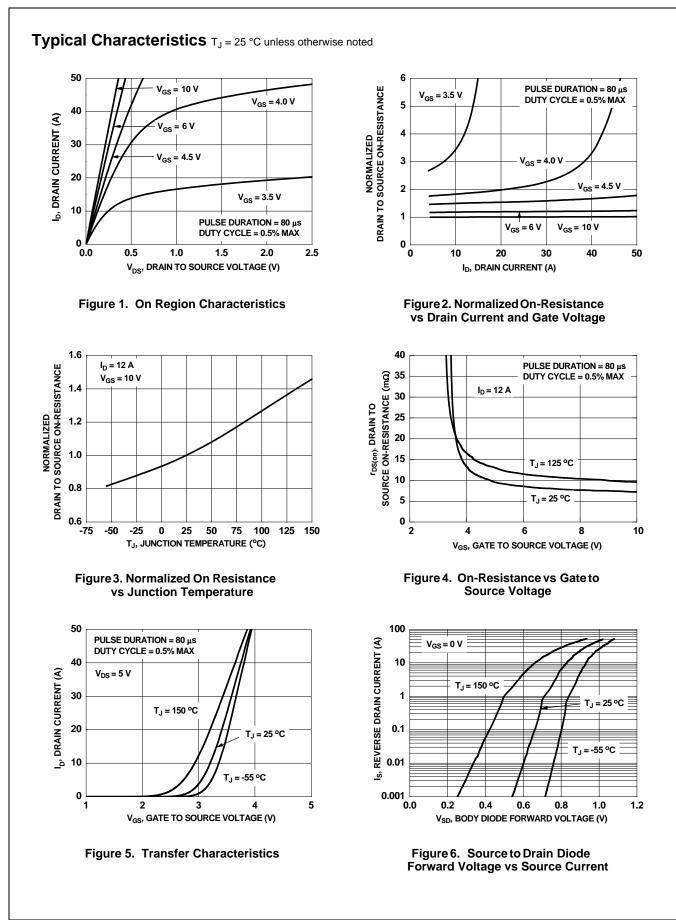
Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMC7696	FDMC7696	MLP 3.3x3.3	13 "	12 mm	3000 units

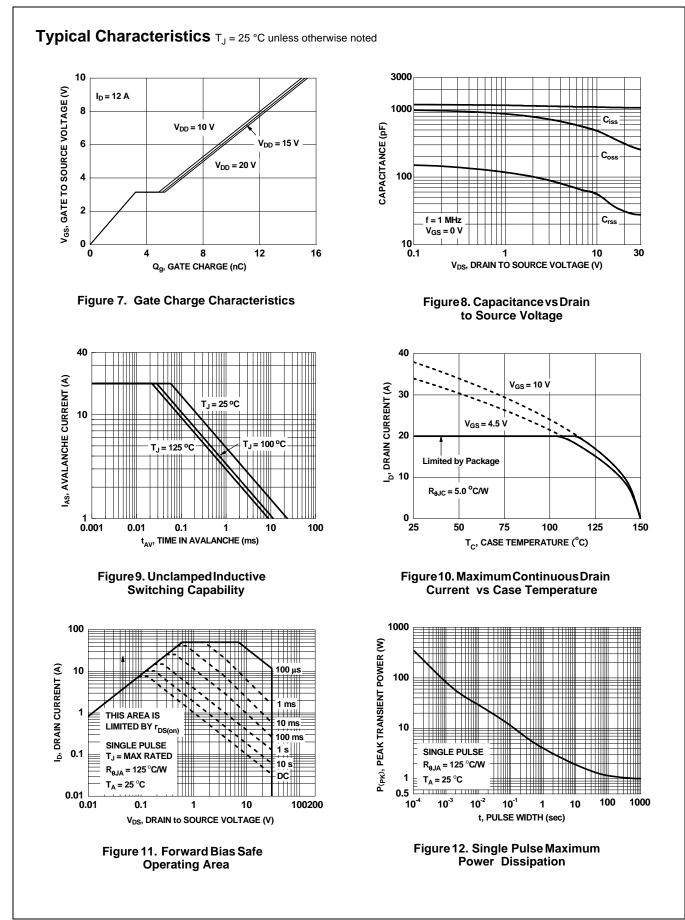
January 2015

FDMC7696 N-Channel PowerTrench
Trench [®]
MOSFET

$ \begin{array}{c c} \Delta BV_{DSS} \\ \hline \Delta T_J \\ \hline D_{DSS} \\ \hline I_{GSS} \\ \hline G_{GSS} \\ \hline On Characterist \\ \hline V_{GS(th)} \\ \hline \Delta V_{GS(th)} \\ \hline \Delta T_J \\ \hline \end{array} \begin{array}{c} Break \\ Coeffic \\ \hline \hline Coeffic \\ \hline Coeffic \\ \hline \hline Coeffic \\ \hline Coeffic \\ \hline Coeffic \\ \hline \hline Coeffic \\ \hline Coeffic \\ \hline Coeffic \\ \hline Coeffic \\ \hline \hline Coeffic \\ \hline Coeffic \\ \hline Coeffic \\ \hline \hline Coeffic \\ \hline Coeffic \\ \hline \hline Coeffic \\ \hline Coeffic \\ \hline \hline \hline Coeffic \\ \hline \hline \hline Coeffic \\ \hline \hline Coeffic \\ \hline \hline \hline Coeffic \\ \hline \hline \hline \hline Coeffic \\ \hline \hline \hline Coeffic \\ \hline \hline \hline \hline \hline Coeffic \\ \hline \hline \hline Coeffic \\ \hline \hline \hline \hline \hline Coeffic \\ \hline \hline \hline \hline Coeffic \\ \hline $	o Source Breakdown Voltage down Voltage Temperature cient Gate Voltage Drain Current o Source Leakage Current, Forward	$\begin{split} I_{D} &= 250 \ \mu\text{A}, \ V_{GS} = 0 \ V \\ I_{D} &= 250 \ \mu\text{A}, \ \text{referenced to } 25 \ ^{\circ}\text{C} \\ V_{DS} &= 24 \ V, \ V_{GS} = 0 \ V \\ V_{GS} &= 20 \ V, \ V_{DS} = 0 \ V \\ \end{split}$	30	2.0	1 100	V mV/°C μA nA
$\begin{array}{c c} \Delta BV_{DSS} & Breakc \\ \hline \Delta T_J & Coeffic \\ \hline I_{DSS} & Zero G \\ \hline I_{GSS} & Gate tr \\ \hline \textbf{On Characterist} \\ \hline V_{GS(th)} & Gate tr \\ \hline \Delta V_{GS(th)} & Gate tr \\ \hline \Delta T_J & Tempe \\ \hline \end{array}$	down Voltage Temperature cient Sate Voltage Drain Current o Source Leakage Current, Forward ics o Source Threshold Voltage o Source Threshold Voltage	$I_{D} = 250 \ \mu\text{A}, \text{ referenced to } 25 \ ^{\circ}\text{C}$ $V_{DS} = 24 \ V, V_{GS} = 0 \ V$ $V_{GS} = 20 \ V, V_{DS} = 0 \ V$ $V_{GS} = V_{DS}, I_{D} = 250 \ \mu\text{A}$			100	mV/°C μA
$\begin{array}{c c} \Delta BV_{DSS} & Breakc \\ \hline \Delta T_J & Coeffic \\ \hline I_{DSS} & Zero G \\ \hline I_{GSS} & Gate tr \\ \hline \textbf{On Characterist} \\ \hline \textbf{V}_{GS(th)} & Gate tr \\ \hline \Delta V_{GS(th)} & Gate tr \\ \hline \Delta T_J & Temperer \\ \hline Control of the second $	down Voltage Temperature cient Sate Voltage Drain Current o Source Leakage Current, Forward ics o Source Threshold Voltage o Source Threshold Voltage	$I_{D} = 250 \ \mu\text{A}, \text{ referenced to } 25 \ ^{\circ}\text{C}$ $V_{DS} = 24 \ V, V_{GS} = 0 \ V$ $V_{GS} = 20 \ V, V_{DS} = 0 \ V$ $V_{GS} = V_{DS}, I_{D} = 250 \ \mu\text{A}$	1.2		100	μA
$\begin{tabular}{ c c c c c }\hline\hline \Delta T_J & Coeffic \\\hline I_{DSS} & Zero G \\\hline I_{GSS} & Gate tr \\\hline \mbox{On Characterist} \\\hline \mbox{On Characterist} \\\hline V_{GS(th)} & Gate tr \\\hline \Delta V_{GS(th)} & Gate tr \\\hline \Delta T_J & Temperer \\\hline \end{tabular}$	ate Voltage Drain Current o Source Leakage Current, Forward ics o Source Threshold Voltage o Source Threshold Voltage	$V_{DS} = 24 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$ $V_{GS} = V_{DS}, I_D = 250 \mu\text{A}$	1.2		100	μA
$\begin{array}{c c} \hline G_{GSS} & Gate tr \\ \hline On Characterist \\ \hline V_{GS(th)} & Gate tr \\ \hline \Delta V_{GS(th)} & Gate tr \\ \hline \Delta T_J & Temper$	b Source Leakage Current, Forward ics b Source Threshold Voltage b Source Threshold Voltage	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$ $V_{GS} = V_{DS}, I_D = 250 \mu\text{A}$	1.2	2.0	100	•
$\begin{array}{c c} \hline \textbf{On Characterist} \\ \hline \textbf{V}_{GS(th)} & \textbf{Gate tr} \\ \hline \Delta \textbf{V}_{GS(th)} & \textbf{Gate tr} \\ \hline \Delta \textbf{T}_J & \textbf{Temperature} \\ \hline \end{array}$	i cs o Source Threshold Voltage o Source Threshold Voltage	V _{GS} = V _{DS} , I _D = 250 μA	1.2	2.0		nA
$\frac{V_{GS(th)}}{\Delta T_{J}} \qquad \begin{array}{c} \text{Gate tr}\\ \text{Gate tr}\\ \text{Temperature}\\ \text{Gate tr}\\ \text{Temperature}\\ \text{Gate tr}\\ \text{Temperature}\\ \text{Gate tr}\\ \text{Temperature}\\ \text{Gate tr}\\ \text{Gate tr}\\ \text{Gate tr}\\ \text{Temperature}\\ \text{Temperature}\\ \text{Gate tr}\\ \text{Temperature}\\ \text{Temperature}\\ \text{Gate tr}\\ \text{Temperature}\\ \text{Gate tr}\\ \text{Temperature}\\ \text{Temperature}\\ \text{Temperature}\\ \text{Gate tr}\\ \text{Temperature}\\ \text{Temperature}\\ \text{Temperature}\\ \text{Temperature}\\ \text{Temperature}\\ \text{Gate tr}\\ \text{Temperature}\\ \text{Temperature}\\ \text{Temperature}\\ \text{Temperature}\\ \text{Gate tr}\\ \text{Temperature}\\ \text{Temperature}$	o Source Threshold Voltage o Source Threshold Voltage		1.2	2.0	0.0	
$\frac{\Delta V_{GS(th)}}{\Delta T_J} \qquad \begin{array}{c} \text{Gate tr}\\ \text{Temper}\\ \end{array}$	o Source Threshold Voltage		1.2	2.0	0.0	
$\frac{\Delta V_{GS(th)}}{\Delta T_J} \qquad \begin{array}{c} \text{Gate tr}\\ \text{Temper}\\ \end{array}$	o Source Threshold Voltage				3.0	V
Tempe	5	$I_D = 250 \ \mu A$, referenced to 25 °C				1/100
r _{DS(on)} Static				-6		mV/°C
r _{DS(on)} Static		V _{GS} = 10 V, I _D = 12 A		8.5	11.5	
DS(on)	Drain to Source On Resistance	V _{GS} = 4.5 V, I _D = 10 A		11.5	14.5	mΩ
	Drain to Source On Resistance	V _{GS} = 10 V, I _D = 12 A,		11.6	15.7	1115.2
-	17	$T_J = 125 \text{ °C}$			10.7	
g _{FS} Forwa	rd Transconductance	$V_{DS} = 5 V, I_D = 12 A$		45		S
Dynamic Chara	cteristics					
C _{iss} Input (Capacitance			1075	1430	pF
	Capacitance	$V_{DS} = 15 V, V_{GS} = 0 V,$		380	505	pF
000	se Transfer Capacitance	f = 1 MHz		40	55	pF
	Resistance	-	0.2	1.0	2.0	Ω
v	4	t			1	
Switching Char				1	1	1
u(011)	on Delay Time			9	18	ns
t _r Rise T		$V_{DD} = 15 V, I_D = 12 A,$		2	10	ns
t _{d(off)} Turn-C	Off Delay Time	V_{GS} = 10 V, R_{GEN} = 6 Ω		19	33	ns
t _f Fall Ti	ne			2	10	ns
9	Sate Charge	$V_{GS} = 0$ V to 10 V		16	22	nC
9	Sate Charge	$V_{GS} = 0 V \text{ to } 5 V$ $V_{DD} = 15 V,$ $I_D = 12 A$		8	11	nC
90	o Source Charge	I _D = 12 A		3.2		nC
Q _{gd} Gate to	o Drain "Miller" Charge			1.8		nC
Drain-Source Di	ode Characteristics					
		V _{GS} = 0 V, I _S = 1.9 A (Note 2)		0.75	1.2	
V _{SD} Source	e to Drain Diode Forward Voltage	$V_{GS} = 0 V, I_S = 12 A$ (Note 2)		0.84	1.2	V
t Revers	se Recovery Time			25	40	ns
	se Recovery Charge	– I _F = 12 A, di/dt = 100 A/μs		9	18	nC
		1 1				

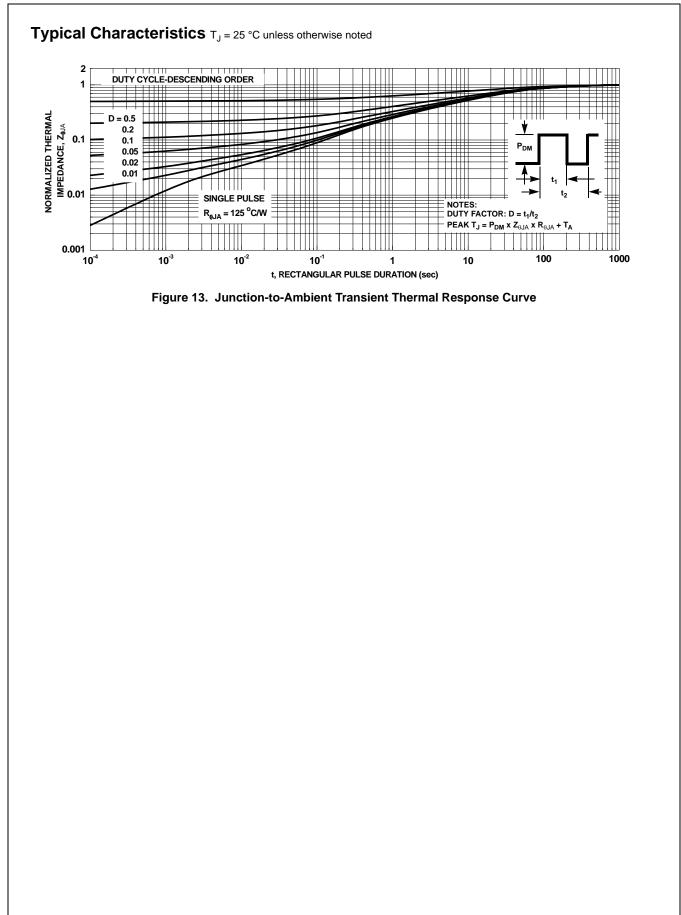




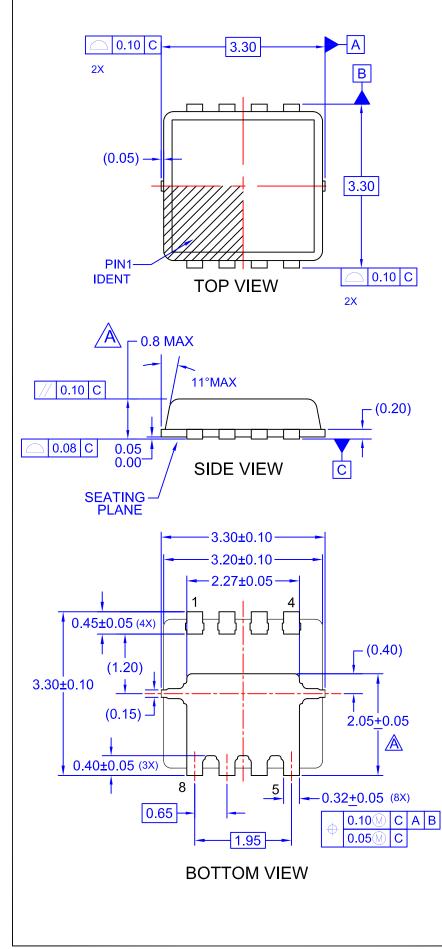


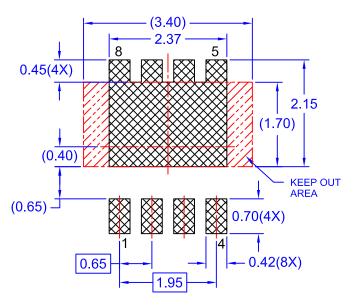
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FDMC7696 N-Channel PowerTrench[®] MOSFET





RECOMMENDED LAND PATTERN

NOTES:

- A EXCEPT AS NOTED, PACKAGE CONFORMS TO JEDEC REGISTRATION MO-240 VARIATION BA.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 2009.
- D. SEATING PLANE IS DEFINED BY TERMINAL TIPS ONLY
- E. BODY DIMENSIONS DO NOT INCLUDE MOLD FLASH PROTRUSIONS NOR GATE BURRS.
- F. FLANGE DIMENSIONS INCLUDE INTERTERMINAL FLASH OR PROTRUSION. INTERTERMINAL FLASH OR PROTRUSION SHALL NOT EXCEED 0.25MM PER SIDE.
- G. IT IS RECOMMENDED TO HAVE NO TRACES OR VIA WITHIN THE KEEP OUT AREA.
- H. DRAWING FILENAME: MKT-MLP08Trev4.
- I. GENERAL RADII FOR ALL CORNERS SHALL BE 0.20MM MAX.





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Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

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